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Substitute for form 1449/PTO				Complete if Known	
				Application Number	09/735,983-Conf. #5697
				Filing Date	December 13, 2000
				First Named Inventor	Seth Haberman
				Art Unit	2611
				Examiner Name	H. V. Tran
Sheet	1	of	2	Attorney Docket Number	2000522.00123US2

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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		Country Code ³ -Number-Kind Code ⁴ (if known)			
					T ⁶

Examiner Signature 6016626	/Hai Tran/ (04/02/2007)	Date Considered
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